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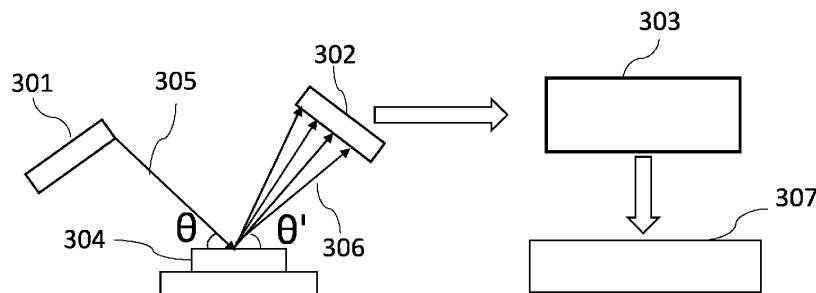


Figure 3

(57) Abstract: A method of non-destructive detection of surface and near surface abnormalities in a metallic product. The method comprises positioning a sample having a surface under a source of an incident radiation. The surface of the sample is then irradiated with the incident radiation from the source. A scattered radiation is detected and a radiation pattern from the detected scattered radiation is produced. Said radiation pattern is then analysed and the output indicative of the scattered radiation from the sample is produced. Said produced output is then compared with a threshold value, the threshold value indicative of a maximum acceptable detected surface abnormality. Finally, the presence of a surface abnormality is identified when the output exceeds the threshold value.

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